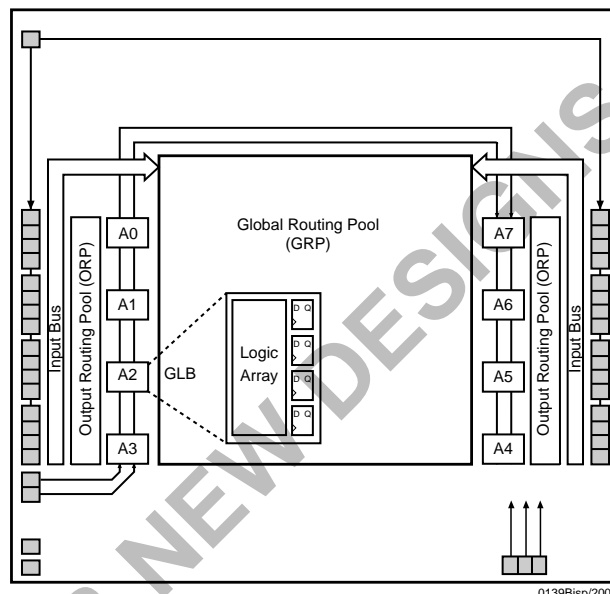


## Features

- **HIGH DENSITY PROGRAMMABLE LOGIC**
  - 1000 PLD Gates
  - 32 I/O Pins, Two Dedicated Inputs
  - 32 Registers
  - High Speed Global Interconnect
  - Wide Input Gating for Fast Counters, State Machines, Address Decoders, etc.
  - Small Logic Block Size for Random Logic
- **3.3V LOW VOLTAGE 2032 ARCHITECTURE**
  - Interfaces With Standard 5V TTL Devices
  - 60 mA Typical Active Current
  - Fuse Map Compatible with 5V ispLSI 2032
- **HIGH PERFORMANCE E<sup>2</sup>CMOS<sup>®</sup> TECHNOLOGY**
  - $f_{max} = 100$  MHz Maximum Operating Frequency
  - $t_{pd} = 7.5$  ns Propagation Delay
  - Electrically Erasable and Reprogrammable
  - Non-Volatile
  - 100% Tested at Time of Manufacture
- **IN-SYSTEM PROGRAMMABLE**
  - 3.3V In-System Programmability Using Boundary Scan Test Access Port (TAP)
  - Open-Drain Output Option for Flexible Bus Interface Capability, Allowing Easy Implementation of Wired-OR or Bus Arbitration Logic
  - Increased Manufacturing Yields, Reduced Time-to-Market and Improved Product Quality
- **THE EASE OF USE AND FAST SYSTEM SPEED OF PLDs WITH THE DENSITY AND FLEXIBILITY OF FPGAs**
  - Enhanced Pin Locking Capability
  - Three Dedicated Clock Input Pins
  - Synchronous and Asynchronous Clocks
  - Programmable Output Slew Rate Control
  - Flexible Pin Placement
  - Optimized Global Routing Pool Provides Global Interconnectivity
- **ispDesignEXPERT<sup>™</sup> – LOGIC COMPILER AND COMPLETE ISP DEVICE DESIGN SYSTEMS FROM HDL SYNTHESIS THROUGH IN-SYSTEM PROGRAMMING**
  - Superior Quality of Results
  - Tightly Integrated with Leading CAE Vendor Tools
  - Productivity Enhancing Timing Analyzer, Explore Tools, Timing Simulator and ispANALYZER<sup>™</sup>
  - PC and UNIX Platforms

## Functional Block Diagram



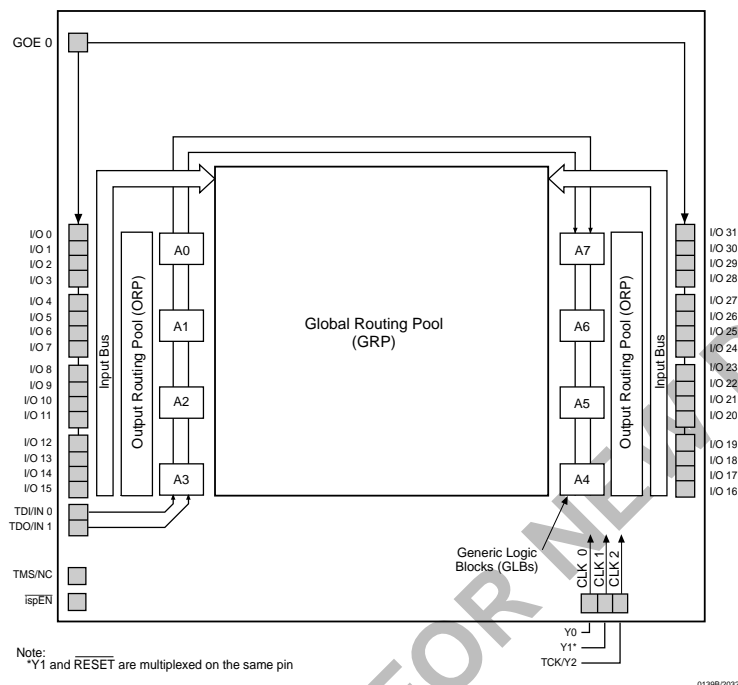
## Description

The ispLSI 2032V is a High Density Programmable Logic Device that can be used in both 3.3V and 5V systems. The device contains 32 Registers, 32 Universal I/O pins, two Dedicated Input Pins, three Dedicated Clock Input Pins, one dedicated Global OE input pin and a Global Routing Pool (GRP). The GRP provides complete interconnectivity between all of these elements. The ispLSI 2032V features in-system programmability through the Boundary Scan Test Access Port (TAP). The ispLSI 2032V offers non-volatile reprogrammability of the logic, as well as the interconnect to provide truly reconfigurable systems.

The basic unit of logic on the ispLSI 2032V device is the Generic Logic Block (GLB). The GLBs are labeled A0, A1 .. A7 (see Figure 1). There are a total of eight GLBs in the ispLSI 2032V device. Each GLB is made up of four macrocells. Each GLB has 18 inputs, a programmable AND/OR/Exclusive OR array, and four outputs which can be configured to be either combinatorial or registered. Inputs to the GLB come from the GRP and dedicated inputs. All of the GLB outputs are brought back into the GRP so that they can be connected to the inputs of any GLB on the device.

## Functional Block Diagram

Figure 1. ispLSI 2032V Functional Block Diagram



The device also has 32 I/O cells, each of which is directly connected to an I/O pin. Each I/O cell can be individually programmed to be a combinatorial input, output or bi-directional I/O pin with 3-state control. The signal levels are TTL compatible voltages and the output drivers can source 4 mA or sink 8 mA. Each output can be programmed independently for fast or slow output slew rate to minimize overall output switching noise. Device pins can be safely driven to 5 Volt signal levels to support mixed-voltage systems.

Eight GLBs, 32 I/O cells, two dedicated inputs and two ORPs are connected together to make a Megablock (see Figure 1). The outputs of the eight GLBs are connected to a set of 32 universal I/O cells by the ORP. Each ispLSI 2032V device contains one Megablock.

The GRP has as its inputs the outputs from all of the GLBs and all of the inputs from the bi-directional I/O cells. All of these signals are made available to the inputs of the GLBs. Delays through the GRP have been equalized to minimize timing skew.

Clocks in the ispLSI 2032V device are selected using the dedicated clock pins. Three dedicated clock pins (Y0, Y1, Y2) or an asynchronous clock can be selected on a GLB

basis. The asynchronous or Product Term clock can be generated in any GLB for its own clock.

### Programmable Open-Drain Outputs

In addition to the standard output configuration, the outputs of the ispLSI 2032V are individually programmable, either as a standard totem-pole output or an open-drain output. The totem-pole output drives the specified  $V_{oh}$  and  $V_{ol}$  levels, whereas the open-drain output drives only the specified  $V_{ol}$ . The  $V_{oh}$  level on the open-drain output depends on the external loading and pull-up. This output configuration is controlled by a programmable fuse. When this fuse is erased (JEDEC "1"), the output is configured as a totem-pole output. When this fuse is programmed (JEDEC "0"), the output is configured as an open-drain. The default configuration when the device is in bulk erased state is totem-pole configuration. The open-drain/totem-pole option is selectable through the ispDesignEXPERT software tools.

## Absolute Maximum Ratings <sup>1</sup>

Supply Voltage  $V_{CC}$  ..... -0.5 to +5.6V  
 Input Voltage Applied ..... -0.5 to +5.6V  
 Off-State Output Voltage Applied ..... -0.5 to +5.6V  
 Storage Temperature ..... -65 to +150°C  
 Case Temp. with Power Applied ..... -55 to 125°C  
 Max. Junction Temp. ( $T_J$ ) with Power Applied ... 150°C

1. Stresses above those listed under the “Absolute Maximum Ratings” may cause permanent damage to the device. Functional operation of the device at these or at any other conditions above those indicated in the operational sections of this specification is not implied (while programming, follow the programming specifications).

## DC Recommended Operating Condition

SYMBOL	PARAMETER		MIN.	MAX.	UNITS
$V_{CC}$	Supply Voltage	Commercial $T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$	3.0	3.6	V
		Industrial $T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$	3.0	3.6	V
$V_{IL}$	Input Low Voltage		$V_{SS} - 0.5$	0.8	V
$V_{IH}$	Input High Voltage		2.0	5.25	V

Table 2 - 0005/2032LV

## Capacitance ( $T_A=25^\circ\text{C}$ , $f=1.0\text{ MHz}$ )

SYMBOL	PARAMETER	TYPICAL	UNITS	TEST CONDITIONS
$C_1$	Dedicated Input Capacitance	8	pf	$V_{CC} = 3.3\text{V}$ , $V_{IN} = 2.0\text{V}$
$C_2$	I/O Capacitance	8	pf	$V_{CC} = 3.3\text{V}$ , $V_{IO} = 2.0\text{V}$
$C_3$	Clock and Global Output Enable Capacitance	13	pf	$V_{CC} = 3.3\text{V}$ , $V_Y = 2.0\text{V}$

Table 2-0006/2032LV

## Data Retention Specifications

PARAMETER	MINIMUM	MAXIMUM	UNITS
Data Retention	20	—	Years
ispLSI Erase/Reprogram Cycles	10000	—	Cycles

Table 2-0008A-2032-isp

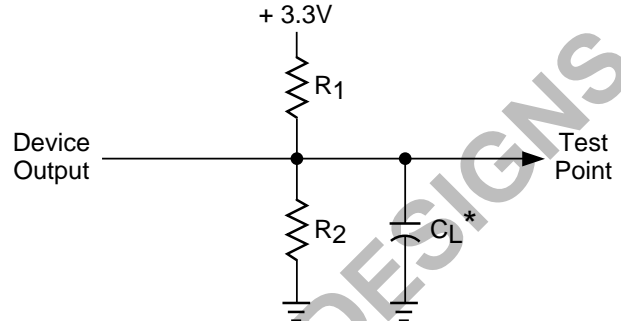
## Switching Test Conditions

Input Pulse Levels	GND to 3.0V
Input Rise and Fall Time 10% to 90%	$\leq 1.5$ ns
Input Timing Reference Levels	1.5V
Output Timing Reference Levels	1.5V
Output Load	See Figure 2

3-state levels are measured 0.5V from steady-state active level.

Table 2-0003/2032V/LV

Figure 2. Test Load



\*CL includes Test Fixture and Probe Capacitance.

0213A

## Output Load Conditions (see figure 2)

TEST CONDITION		R1	R2	CL
A		316Ω	348Ω	35pF
B	Active High	∞	348Ω	35pF
	Active Low	316Ω	348Ω	35pF
C	Active High to Z at $V_{OH}-0.5V$	∞	348Ω	5pF
	Active Low to Z at $V_{OL}+0.5V$	316Ω	348Ω	5pF

Table 2 - 0004A

## DC Electrical Characteristics

### Over Recommended Operating Conditions

SYMBOL	PARAMETER	CONDITION	MIN.	TYP. <sup>3</sup>	MAX.	UNITS
<b>V<sub>OL</sub></b>	Output Low Voltage	$I_{OL} = 8$ mA	—	—	0.4	V
<b>V<sub>OH</sub></b>	Output High Voltage	$I_{OH} = -4$ mA	2.4	—	—	V
<b>I<sub>IL</sub></b>	Input or I/O Low Leakage Current	$0V \leq V_{IN} \leq V_{IL} (Max.)$	—	—	-10	μA
<b>I<sub>IH</sub></b>	Input or I/O High Leakage Current	$(V_{CC} - 0.2)V \leq V_{IN} \leq V_{CC}$	—	—	10	μA
		$V_{CC} \leq V_{IN} \leq 5.25V$	—	—	50	mA
<b>I<sub>IL-isp</sub></b>	ispEN Input Low Leakage Current	$0V \leq V_{IN} \leq V_{IL}$	—	—	-150	μA
<b>I<sub>IL-PU</sub></b>	I/O Active Pull-Up Current	$0V \leq V_{IN} \leq V_{IL}$	—	—	-150	μA
<b>I<sub>OS</sub><sup>1</sup></b>	Output Short Circuit Current	$V_{CC} = 3.3V, V_{OUT} = 0.5V$	—	—	-100	mA
<b>I<sub>CC</sub><sup>2,4</sup></b>	Operating Power Supply Current	$V_{IL} = 0.0V, V_{IH} = 3.0V$ $f_{TOGGLE} = 1$ MHz	—	60	—	mA

Table 2-0007/2032V

- One output at a time for a maximum duration of one second.  $V_{OUT} = 0.5V$  was selected to avoid test problems by tester ground degradation. Characterized but not 100% tested.
- Measured using two 16-bit counters.
- Typical values are at  $V_{CC} = 3.3V$  and  $T_A = 25^\circ C$ .
- Maximum  $I_{CC}$  varies widely with specific device configuration and operating frequency. Refer to Power Consumption section of this data sheet and Thermal Management section of the Lattice Semiconductor Data Book or CD-ROM to estimate maximum  $I_{CC}$ .

## External Timing Parameters

Over Recommended Operating Conditions

PARAMETER	TEST COND. <sup>4</sup>	# <sup>2</sup>	DESCRIPTION <sup>1</sup>	-100		-80		-60		UNITS
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
t <sub>pd1</sub>	A	1	Data Propagation Delay, 4PT Bypass, ORP Bypass	–	7.5	–	10.0	–	15.0	ns
t <sub>pd2</sub>	A	2	Data Propagation Delay	–	12.0	–	15.0	–	20.0	ns
f <sub>max</sub>	A	3	Clock Frequency with Internal Feedback <sup>3</sup>	100	–	80.0	–	61.7	–	MHz
f <sub>max</sub> (Ext.)	–	4	Clock Frequency with External Feedback ( $\frac{1}{t_{su2} + t_{co1}}$ )	83.3	–	64.5	–	51.3	–	MHz
f <sub>max</sub> (Tog.)	–	5	Clock Frequency, Max. Toggle	125	–	100	–	71.4	–	MHz
t <sub>su1</sub>	–	6	GLB Reg. Setup Time before Clock, 4 PT Bypass	5.5	–	7.0	–	9.0	–	ns
t <sub>co1</sub>	A	7	GLB Reg. Clock to Output Delay, ORP Bypass	–	5.0	–	6.5	–	8.5	ns
t <sub>h1</sub>	–	8	GLB Reg. Hold Time after Clock, 4 PT Bypass	0.0	–	0.0	–	0.0	–	ns
t <sub>su2</sub>	–	9	GLB Reg. Setup Time before Clock	7.0	–	9.0	–	11.0	–	ns
t <sub>co2</sub>	–	10	GLB Reg. Clock to Output Delay	–	6.5	–	7.5	–	9.5	ns
t <sub>h2</sub>	–	11	GLB Reg. Hold Time after Clock	0.0	–	0.0	–	0.0	–	ns
t <sub>r1</sub>	A	12	Ext. Reset Pin to Output Delay	–	12.0	–	14.0	–	16.0	ns
t <sub>rw1</sub>	–	13	Ext. Reset Pulse Duration	5.0	–	7.0	–	8.0	–	ns
t <sub>ptoen</sub>	B	14	Input to Output Enable	–	13.0	–	15.0	–	18.0	ns
t <sub>ptoedis</sub>	C	15	Input to Output Disable	–	13.0	–	15.0	–	18.0	ns
t <sub>goeen</sub>	B	16	Global OE Output Enable	–	7.5	–	10.0	–	12.0	ns
t <sub>goedis</sub>	C	17	Global OE Output Disable	–	7.5	–	10.0	–	12.0	ns
t <sub>wh</sub>	–	18	External Synchronous Clock Pulse Duration, High	4.0	–	5.0	–	7.0	–	ns
t <sub>wl</sub>	–	19	External Synchronous Clock Pulse Duration, Low	4.0	–	5.0	–	7.0	–	ns

Table 2-0030/2032V

1. Unless noted otherwise, all parameters use the GRP, 20 PTXOR path, ORP and Y0 clock.

2. Refer to Timing Model in this data sheet for further details.

3. Standard 16-bit counter using GRP feedback.

4. Reference Switching Test Conditions section.

## Internal Timing Parameters<sup>1</sup>

Over Recommended Operating Conditions

PARAMETER	# <sup>2</sup>	DESCRIPTION	-100		-80		-60		UNITS
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Inputs									
tio	20	Input Buffer Delay	–	0.2	–	0.4	–	0.6	ns
tdin	21	Dedicated Input Delay	–	0.6	–	1.3	–	1.4	ns
GRP									
tgrp	22	GRP Delay	–	0.7	–	1.2	–	2.1	ns
GLB									
t4ptbpc	23	4 Product Term Bypass Path Delay (Combinatorial)	–	4.6	–	5.8	–	9.6	ns
t4ptbpr	24	4 Product Term Bypass Path Delay (Registered)	–	6.0	–	7.5	–	10.3	ns
t1ptxor	25	1 Product Term/XOR Path Delay	–	6.7	–	9.2	–	12.3	ns
t20ptxor	26	20 Product Term/XOR Path Delay	–	7.5	–	9.5	–	12.3	ns
txoradj	27	XOR Adjacent Path Delay <sup>3</sup>	–	8.5	–	11.3	–	14.4	ns
tgbp	28	GLB Register Bypass Delay	–	0.3	–	0.3	–	1.3	ns
tgsu	29	GLB Register Setup Time befor Clock	0.1	–	0.2	–	0.2	–	ns
tgh	30	GLB Register Hold Time after Clock	3.8	–	5.4	–	8.0	–	ns
tgco	31	GLB Register Clock to Output Delay	–	1.5	–	1.6	–	1.6	ns
tgro	32	GLB Register Reset to Output Delay	–	2.2	–	2.5	–	2.8	ns
tptre	33	GLB Product Term Reset to Register Delay	–	3.8	–	5.6	–	9.3	ns
tp toe	34	GLB Product Term Output Enable to I/O Cell Delay	–	7.2	–	8.5	–	10.4	ns
tp tck	35	GLB Product Term Clock Delay	3.0	4.4	3.8	5.6	6.5	9.3	ns
ORP									
torp	36	ORP Delay	–	1.4	–	1.4	–	1.5	ns
torpbp	37	ORP Bypass Delay	–	0.1	–	0.4	–	0.5	ns
Outputs									
tob	38	Output Buffer Delay	–	1.9	–	2.2	–	2.2	ns
tsl	39	Output Slew Limited Delay Adder	–	11.9	–	12.2	–	12.2	ns
toen	40	I/O Cell OE to Output Enabled	–	4.9	–	4.9	–	4.9	ns
todis	41	I/O Cell OE to Output Disabled	–	4.9	–	4.9	–	4.9	ns
tgoe	42	Global Output Enable	–	2.6	–	5.1	–	7.1	ns
Clocks									
tgy0	43	Clock Delay, Y0 to Global GLB Clock Line (Ref. clock)	1.5	1.5	2.3	2.3	4.2	4.2	ns
tgy1/2	44	Clock Delay, Y1 or Y2 to Global GLB Clock Line	1.5	1.5	2.3	2.3	4.2	4.2	ns
Global Reset									
tgr	45	Global Reset to GLB	–	6.5	–	7.9	–	9.5	ns

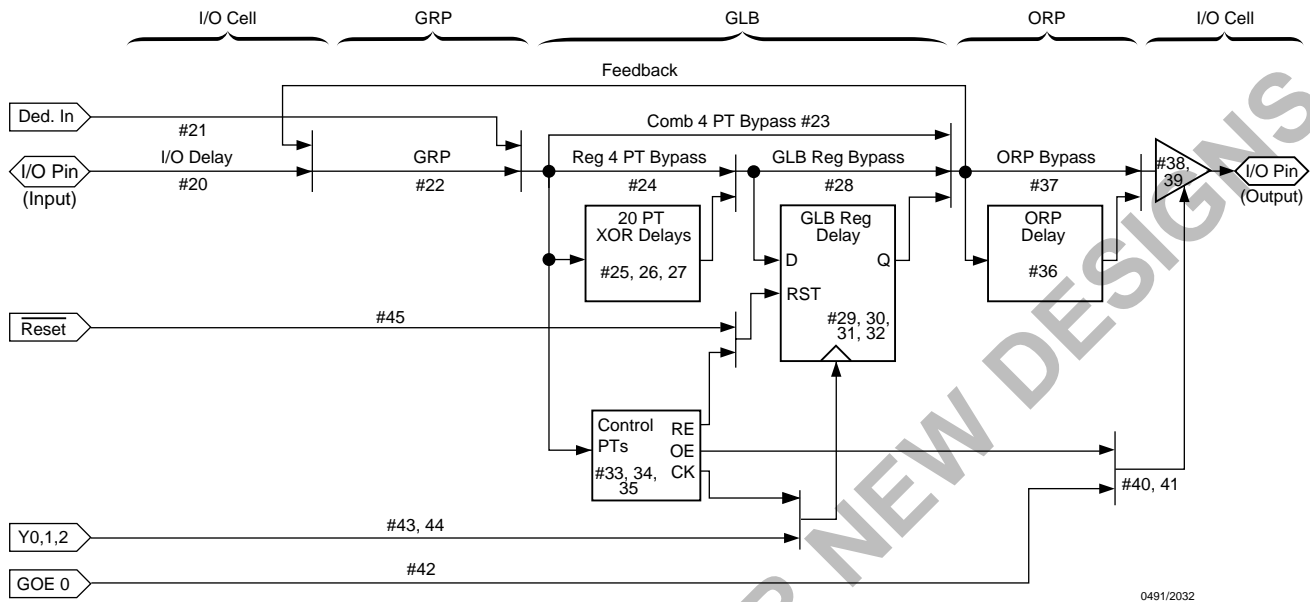
1. Internal Timing Parameters are not tested and are for reference only.

Table 2-0036/2032V

2. Refer to Timing Model in this data sheet for further details.

3. The XOR adjacent path can only be used by hard macros.

**ispLSI 2032V Timing Model**



**Derivations of  $t_{su}$ ,  $t_h$  and  $t_{co}$  from the Product Term Clock<sup>1</sup>**

$$\begin{aligned}
 t_{su} &= \text{Logic} + \text{Reg } su - \text{Clock (min)} \\
 &= (t_{io} + t_{grp} + t_{20ptxor}) + (t_{gsu}) - (t_{io} + t_{grp} + t_{ptck(min)}) \\
 &= (\#20 + \#22 + \#26) + (\#29) - (\#20 + \#22 + \#35) \\
 4.6 \text{ ns} &= (0.2 + 0.7 + 7.5) + (0.1) - (0.2 + 0.7 + 3.0) \\
 t_h &= \text{Clock (max)} + \text{Reg } h - \text{Logic} \\
 &= (t_{io} + t_{grp} + t_{ptck(max)}) + (t_{gh}) - (t_{io} + t_{grp} + t_{20ptxor}) \\
 &= (\#20 + \#22 + \#35) + (\#30) - (\#20 + \#22 + \#26) \\
 0.7 \text{ ns} &= (0.2 + 0.7 + 4.4) + (3.8) - (0.2 + 0.7 + 7.5) \\
 t_{co} &= \text{Clock (max)} + \text{Reg } co + \text{Output} \\
 &= (t_{io} + t_{grp} + t_{ptck(max)}) + (t_{gco}) + (t_{orp} + t_{ob}) \\
 &= (\#20 + \#22 + \#35) + (\#31) + (\#36 + \#38) \\
 10.1 \text{ ns} &= (0.2 + 0.7 + 4.4) + (1.5) + (1.4 + 1.9)
 \end{aligned}$$

Note: Calculations are based on timing specifications for the ispLSI 2032V-100.

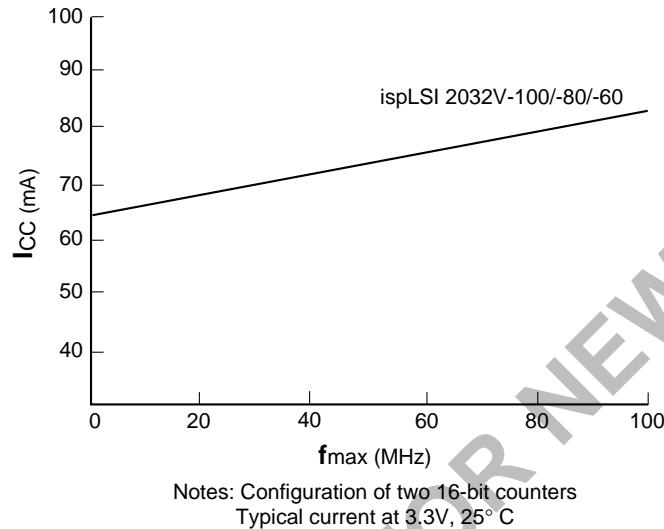
Table 2-0042/2032V

## Power Consumption

Power consumption in the ispLSI 2032V device depends on two primary factors: the speed at which the device is operating and the number of product terms used. Figure

3 shows the relationship between power and operating speed.

**Figure 3. Typical Device Power Consumption vs fmax**



ICC can be estimated for the ispLSI 2032V using the following equation:

$$I_{CC}(\text{mA}) = 15 + (\# \text{ of PTs} * 0.78) + (\# \text{ of nets} * \text{Max freq} * 0.004)$$

Where:

# of PTs = Number of product terms used in design

# of nets = Number of signals used in device

Max freq = Highest clock frequency to the device (in MHz)

The ICC estimate is based on typical conditions (VCC = 3.3V, room temperature) and an assumption of two GLB loads on average exists. These values are for estimates only. Since the value of ICC is sensitive to operating conditions and the program in the device, the actual ICC should be verified.

0127A/2032V

## Power-up Considerations

When Lattice 3.3V 2000V devices are used in mixed 5V/3.3V applications, some consideration needs to be given to the power-up sequence. When the I/O pins on the 3.3V ispLSI devices are driven directly by 5V devices, a low impedance path can exist on the 3.3V device between its I/O and Vcc pins when the 3.3V supply is not present. This low impedance path can cause current to flow from the 5V device into the 3.3V ispLSI device. The maximum current occurs when the signals on the I/O pins are driven high by the 5V devices. If a large enough current flows through the 3.3V I/O pins, latch-up can occur and permanent device damage may result.

This latch-up condition occurs only during the power-up sequence when the 5V supply comes up before the 3.3V supply. The Lattice 3.3V ispLSI devices are guaranteed to withstand 5V interface signals within the device operating Vcc range of 3.0V to 3.6V.

The recommended power-up options are as follows:

Option 1: Ensure that the 3.3V supply is powered-up and stable before the 5V supply is powered up.

Option 2: Ensure that the 5V device outputs are driven to a high impedance or logic low state during power-up.



## Pin Description

NAME	PLCC PIN NUMBERS	DESCRIPTION
I/O 0 - I/O 3 I/O 4 - I/O 7 I/O 8 - I/O 11 I/O 12 - I/O 15 I/O 16 - I/O 19 I/O 20 - I/O 23 I/O 24 - I/O 27 I/O 28 - I/O 31	15, 16, 17, 18, 19, 20, 21, 22, 25, 26, 27, 28, 29, 30, 31, 32, 37, 38, 39, 40, 41, 42, 43, 44, 3, 4, 5, 6, 7, 8, 9, 10	Input/Output Pins — These are the general purpose I/O pins used by the logic array.
GOE 0	2	Global Output Enable input pin.
Y0  RESET/Y1	11  35	Dedicated Clock input. This clock input is connected to one of the clock inputs of all the GLBs on the device.  This pin performs two functions: - Dedicated clock input. This clock input is brought into the Clock Distribution Network, and can optionally be routed to any GLB and/or I/O cell on the device. - Active Low (0) Reset pin which resets all of the GLB and I/O registers in the device.
ispEN  TDI/IN 0  TMS/NC <sup>1</sup> TDO/IN 1  TCK/Y2	13  14  36 24  33	Input — Dedicated in-system programming Boundary Scan Enable input pin. This pin is brought low to enable the programming mode. The TMS, TDI, TDO and TCK controls become active.  Input — This pin performs two functions. When $\overline{\text{ispEN}}$ is logic low, it functions as an input pin to load programming data into the device. TDI/IN0 also is used as one of the two control pins for the isp state machine. When $\overline{\text{ispEN}}$ is high, it functions as a dedicated input pin.  Input — When in ISP Mode, controls operation of ISP state-machine.  Output/Input — This pin performs two functions. When $\overline{\text{ispEN}}$ is logic low, it functions as an output pin to read serial shift register data. When $\overline{\text{ispEN}}$ is high, it functions as a dedicated input pin.  Input — This pin performs two functions. When $\overline{\text{ispEN}}$ is logic low, it functions as a clock pin for the Serial Shift Register. When $\overline{\text{ispEN}}$ is high, it functions as a dedicated clock input. This clock input is brought into the Clock Distribution Network, and can optionally be routed to any GLB and/or I/O cell on the device.
GND VCC	1, 23 12, 34	Ground (GND) V <sub>CC</sub>

1. NC pins are not to be connected to any active signals, VCC or GND.

Table 2-0002A/2032V

## Pin Description

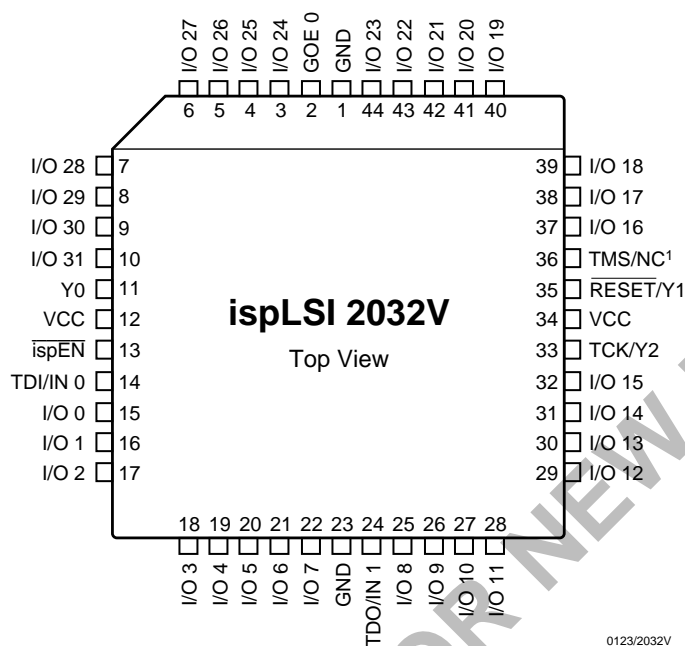
NAME	TQFP PIN NUMBERS	DESCRIPTION
I/O 0 - I/O 3 I/O 4 - I/O 7 I/O 8 - I/O 11 I/O 12 - I/O 15 I/O 16 - I/O 19 I/O 20 - I/O 23 I/O 24 - I/O 27 I/O 28 - I/O 31	9, 10, 11, 12, 13, 14, 15, 16, 19, 20, 21, 22, 23, 24, 25, 26, 31, 32, 33, 34, 35, 36, 37, 38, 41, 42, 43, 44, 1, 2, 3, 4	Input/Output Pins — These are the general purpose I/O pins used by the logic array.
GOE 0	40	Global Output Enable input pin.
Y0	5	Dedicated Clock input. This clock input is connected to one of the clock inputs of all the GLBs on the device.
$\overline{\text{RESET}}/\text{Y1}$	29	This pin performs two functions: - Dedicated clock input. This clock input is brought into the Clock Distribution Network, and can optionally be routed to any GLB and/or I/O cell on the device. - Active Low (0) Reset pin which resets all of the GLB and I/O registers in the device.
$\overline{\text{ispEN}}$	7	Input — Dedicated in-system programming Boundary Scan enable input pin. This pin is brought low to enable the programming mode. The TMS, TDI, TDO and TCK controls become active.
TDI/IN 0	8	Input — This pin performs two functions. When $\overline{\text{ispEN}}$ is logic low, it functions as an input pin to load programming data into the device. TDI/IN0 also is used as one of the two control pins for the isp state machine. When $\overline{\text{ispEN}}$ is high, it functions as a dedicated input pin.
TMS/NC <sup>1</sup>	30	Input — When in ISP Mode, controls operation of ISP state-machine.
TDO/IN 1	18	Output/Input — This pin performs two functions. When $\overline{\text{ispEN}}$ is logic low, it functions as an output pin to read serial shift register data. When $\overline{\text{ispEN}}$ is high, it functions as a dedicated input pin.
TCK/Y2	27	Input — This pin performs two functions. When $\overline{\text{ispEN}}$ is logic low, it functions as a clock pin for the Serial Shift Register. It is a dedicated clock input when $\overline{\text{ispEN}}$ is logic high. This clock input is brought into the Clock Distribution Network, and can optionally be routed to any GLB and/or I/O cell on the device.
GND	17, 39	Ground (GND)
VCC	6, 28	V <sub>CC</sub>

Table 2-0002B/2032V

1. NC pins are not to be connected to any active signals, VCC or GND.

## Pin Configuration

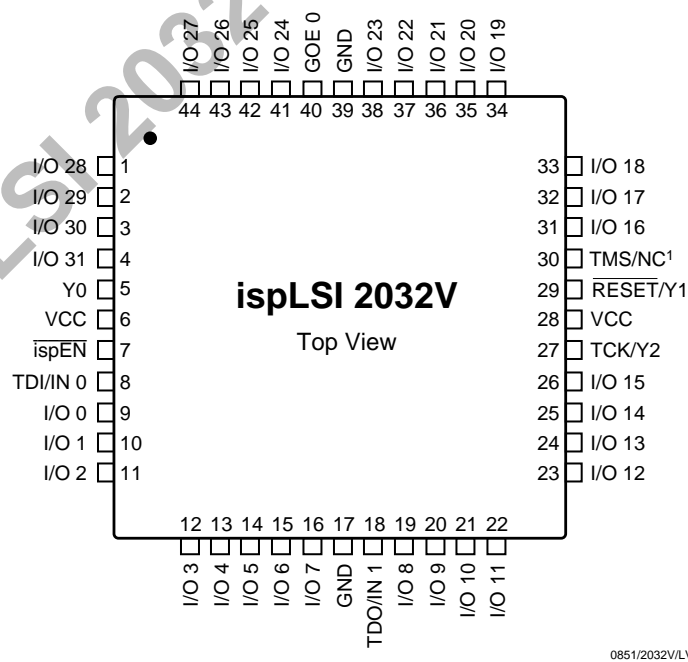
ispLSI 2032V 44-Pin PLCC Pinout Diagram



1. NC pins are not to be connected to any active signals, VCC or GND.

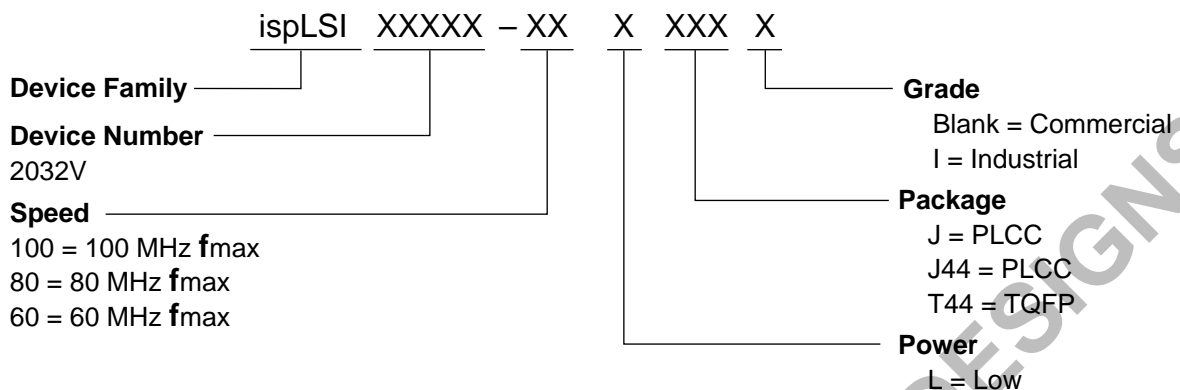
## Pin Configuration

ispLSI 2032V 44-Pin TQFP Pinout Diagram



1. NC pins are not to be connected to any active signals, VCC or GND.

**Part Number Description**



0212/2032V

**ispLSI 2032V Ordering Information**

**COMMERCIAL**

FAMILY	$f_{max}$ (MHz)	tpd (ns)	ORDERING NUMBER	PACKAGE
ispLSI	100	7.5	ispLSI 2032V-100LJ44	44-Pin PLCC
	100	7.5	ispLSI 2032V-100LT44	44-Pin TQFP
	80	10	ispLSI 2032V-80LJ44	44-Pin PLCC
	80	10	ispLSI 2032V-80LT44	44-Pin TQFP
	60	15	ispLSI 2032V-60LJ44	44-Pin PLCC
	60	15	ispLSI 2032V-60LT44	44-Pin TQFP

Table 2-0041A/2032V

**INDUSTRIAL**

FAMILY	$f_{max}$ (MHz)	tpd (ns)	ORDERING NUMBER	PACKAGE
ispLSI	60	15	ispLSI 2032V-60LJ44I	44-Pin PLCC
	60	15	ispLSI 2032V-60LT44I	44-Pin TQFP

Table 2-0041B/2032V